

ELASTIC PROPERTIES OF PRASEODYMIUM ORTHOVANADATE

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Rare-earth orthovanadates (RVO₄) are known to be applicable as laser materials. Their physical properties lead to applications in other optical devices, gas sensors, phosphors, polarizers, etc.; they are also useful in catalysis [1]-[6]. At ambient conditions RVO₄ adopt the zircon structure (space group $I4_1/amd$), except for LaVO₄ exhibiting polymorphism depending on preparation conditions. In the 5 – 10 GPa pressure range these materials undergo a phase transition from zircon to scheelite-type structure.

The aim of the present investigation was to determine the elastic properties of PrVO₄ at pressures from ambient up to 5 GPa, using the synchrotron beam, and to verify whether the zircon-scheelite phase transition occurs at the applied conditions. For this purpose, energy dispersive data at high-pressure conditions were collected using white synchrotron radiation at the F2.1 beamline Hasylab/DESY (Hamburg, Germany). The in-situ powder-diffraction experiments were carried out using the MAX80 X-ray diffraction press. The data were collected using a germanium solid-state detector. The diffraction angle was fixed at angle 3.793°. For calibration of the applied pressure NaCl powder was used. Unit cell parameters for PrVO₄ were refined using the Le Bail method. Bulk modulus was calculated from fitting of the second order Birch-Murnaghan equation of state.

The studied needle-shaped single crystal was grown by slow cooling of the molten PbO/PbF₂ flux. For high-pressure powder diffraction experiment, this crystal was finely ground in an agate mortar. In order to reduce strains in the diffraction experiment, the obtained powder was mixed with vaseline in volume proportion 1:1.

At ambient conditions, the lattice parameters of the studied zircon-type PrVO₄ crystal are in good agreement with literature data. In pressure range from ambient up to 5 GPa, the observed lattice

parameters smoothly decrease with increasing pressure; the total decrease of the unit-cell volume is at the level of 4.5%. Phase transition to scheelite structure is not observed within the studied pressure range.

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